

<b>Notice of References Cited</b>	Application/Control No. 09/575,139	Applicant(s)/Patent Under Reexamination LAPSTUN ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,158,747 A	06-1979	Muller et al.	178/19.03
	B	US-4,739,377 A	04-1988	Allen, James D.	355/133
	C	US-5,235,654 A	08-1993	Anderson et al.	382/180
	D	US-5,742,705 A	04-1998	Parthasarathy, Kannan	382/185
	E	US-5,751,470 A	05-1998	Damon, Brian Wesley	358/3.23
	F	US-5,777,605 A	07-1998	Yoshinobu et al.	345/173
	G	US-5,848,426 A	12-1998	Wang et al.	715/505
	H	US-6,005,973 A	12-1999	Seybold et al.	382/187
	I	US-6,021,217 A	02-2000	Nakahara, Nobuhiko	382/169
	J	US-6,035,308 A	03-2000	Yano et al.	715/501.1
	K	US-6,129,278 A	10-2000	Wang et al.	235/462.01
	L	US-6,603,864 B1	08-2003	Matsunoshita, Junichi	382/100
	M	US-6,885,769 B2	04-2005	Morita et al.	382/181

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,501,931 A	02-1985	Ohya et al.	345/175
	B	US-4,532,596 A	07-1985	Pugsley, Peter C.	700/125
	C	US-5,438,430 A	08-1995	Mackinlay et al.	358/450
	D	US-5,544,265 A	08-1996	Bozinovic et al.	382/203
	E	US-5,630,168 A	05-1997	Rosebrugh et al.	710/5
	F	US-5,822,546 A	10-1998	George, Stanley W.	710/303
	G	US-5,943,137 A	08-1999	Larson et al.	358/403
	H	US-5,945,972 A	08-1999	Okumura et al.	345/98
	I	US-5,995,193 A	11-1999	Stephany et al.	355/31
	J	US-6,100,996 A	08-2000	Amano et al.	358/1.9
	K	US-6,456,740 B1	09-2002	Carini et al.	382/187
	L	US-6,490,681 B1	12-2002	Kobayashi et al.	713/171
	M	US-2003/0007661 A1	01-2003	NOGUCHI, YASUTAKA	382/100

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	S					
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,918,029	11-1975	Lemelson, Jerome H.	235/472.03
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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